



National Standards Authority of Ireland

IRISH STANDARD

I.S. EN 153000:1998

ICS 31.080

**GENERIC SPECIFICATION: DISCRETE
PRESSURE CONTACT POWER
SEMICONDUCTOR DEVICES (QUALIFICATION
APPROVAL)**

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

This European Standard was prepared by CECC Working Group 7 "Rectifier diodes and thyristors". In the absence of a current chairman or secretary of CECC Working Group 7, this specification was submitted to the CECC by the UK ONH under the Single Originator Procedure. It is based whenever possible on the publications of International Electrotechnical Commission (IEC) and in particular on those referred to under "Related Documents".

The text of the draft was submitted to the Unique Acceptance Procedure and was approved by CENELEC as EN 153000 on 1995-11-28.

The following dates were fixed:

- latest date by which the EN has to be implemented
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- latest date by which the national standards conflicting
with the EN have to be withdrawn (dow) 1998-11-01

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1 General

1.1 Scope

This document applies to discrete pressure contact power semiconductor devices namely rectifier diodes, transistors, thyristors and their derivatives. The requirements also cover encapsulated assemblies. The document does not apply to stacks or assemblies made with these encapsulated components.

1.2 Related documents

CECC 00 007	Basic specification: Sampling plans and procedures for inspection attributes
CECC 00 111	RP 11: Specifications
EN 100114-1	Rule of procedure - Quality Assessment Procedures Part 1: CECC requirements for the approval of an organization
EN 100114-2	Part 2: CECC requirements for the qualification approval, the release for delivery and the validity of release of electronic components
IEC 60027	Letters symbols to be used in electrical technology (several parts)
IEC 60050	International Electrotechnical Vocabulary
IEC 60068	Basic environmental testing procedures, namely:
IEC 60068-1	Part 1: General
IEC 60068-2-2	Dry heat: Test Ba
IEC 60068-2-6	Vibration (sinusoidal): Test Fc
IEC 60068-2-14	Change of temperature: Tests Na, Nb and Nc
IEC 60068-2-17	Sealing: Tests Qc, Qk and Ql
IEC 60148	Letter symbols for semiconductor devices and integrated microcircuits
IEC 60191	Mechanical standardization of semiconductor devices (several parts)
IEC 60410	Sampling plans and procedures for inspection of attributes (see also CECC 00 007)
IEC 60617	Graphical symbols for diagrams
IEC 60747-2	Semiconductor devices and integrated circuits Part 2. Rectifier diodes
IEC 60747-6	Semiconductor devices and integrated circuits Part 6. Thyristors

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